

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10537155	LEE ET AL.
	<b>Examiner</b>  O'Reilly III, Patrick F	<b>Art Unit</b>  3749

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
454	284, 299, 305	12/20/2006	PFO3
62	186	12/20/2006	PFO3

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (USPAT, USPGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB) searched - printout attached.	12/20/2006	PFO3
PLUS search performed - printout of search results attached.	12/20/2006	STIC
Inventor name search performed in PALM and EAST.	12/19/2006; 12/21/2006	PFO3

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>